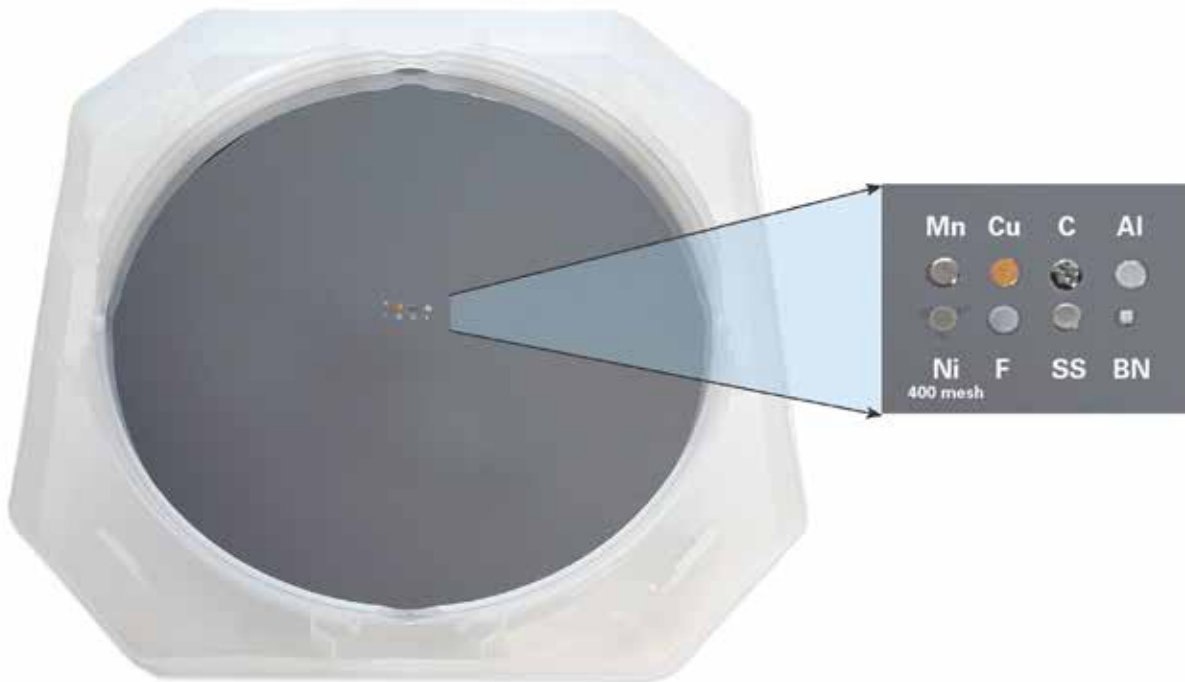


# **NEW PELCO X-CHECKER™ WAFER**



The PELCO X-Checker™ Wafer is available for systems set up for silicon wafer handling. The PELCO X-Checker™ Wafer is available on standard 200mm (8") and 300mm (12") wafers, with eight standards for elemental and spatial calibrations.

The #602-20 and #602-21 contain:

- Copper disc to check spectral calibration
- Manganese 88%, nickel 2% alloy to measure full width at half max (FWHM) detector resolution
- Nickel 400 mesh TEM grid for imaging calibration
- PTFE as a fluorine source to measure low energy resolution
- Carbon to monitor calibration at the low end of the spectrum for thin window detectors
- Aluminum foil disc
- Boron nitride to test low energy performance/peak separation
- Stainless steel for checking quantification

602-20	PELCO X-Checker™ Wafer, 200mm (8") .....	each
602-21	PELCO X-Checker™ Wafer, 300mm (12") .....	each